

What is claimed is:

1. A hard magnetic film structural body, comprising:

a substrate having a main surface;

5 a crystal metal base film formed on the main surface of
said substrate;

an amorphous layer formed between said substrate and said
crystal metal base film; and

10 a hard magnetic film formed on said crystal metal base
film and containing Co as a structural element, said hard
magnetic film having a bi-crystal structure.

2. The hard magnetic film structural body as set forth
in claim 1,

15 wherein said amorphous layer is a reactive layer of the
substrate and the crystal metal base film.

3. The hard magnetic film structural body as set forth
in claim 1,

20 farther comprising a reactive metal crystal layer
disposed between the crystal metal base film and the amorphous
layer.

4. The hard magnetic film structural body as set forth
in claim 1,

25 wherein said substrate has a surface layer on the main
surface side, the surface layer being composed of at least one
selected from the group consisting of an oxide, a nitride, and
a carbide.

5. The hard magnetic film structural body as set forth
in claim 1,

wherein said hard magnetic film containing Co as a

Subj 5 structural element has Co(110) oriented perpendicular to the
surface thereof.

6. The hard magnetic film structural body as set forth
in claim 1,

5 wherein said crystal metal base film contains at least
one element selected from the group consisting of Cr, V, Ti,
Ta, W, Zr, Nb, Hf, Mo, and Al.

10 7. The hard magnetic film structural body as set forth
in claim 1,

wherein said crystal metal base film has a bcc (200)
orientation component.

15 8. The hard magnetic film structural body as set forth
in claim 1,

wherein the total film thickness of said crystal metal
base film and said amorphous layer is 50 nm or less.

20 9. The hard magnetic film structural body as set forth
in claim 1,

wherein the average diameter of crystal grains of said
crystal metal base film is five times or more the thickness
25 thereof.

10. The hard magnetic film structural body as set forth
in claim 1,

wherein said hard magnetic film has main-grains and sub-
grains, the diameter of the main-grain being 50 nm or more,
25 each of the main-grains having the sub-grains.

11. The hard magnetic film structural body as set forth
in claim 1,

wherein said crystal metal base film and said amorphous

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layer are magnetic layers.

12. A hard magnetic film structural body, comprising:

a substrate having a main surface;

a crystal metal base film formed on the main surface of
said substrate;

a mixing layer formed between said substrate and said
crystal metal base film and containing structural elements of
said substrate and structural elements of said crystal metal
base film; and

10 a hard magnetic film formed on said crystal metal base
film and containing Co as a structural element, said hard
magnetic film having a bi-crystal structure.

13. The hard magnetic film structural body as set forth
in claim 12,

15 wherein said substrate has a surface layer on the main
surface side, the surface layer being composed of at least one
selected from the group consisting of an oxide, a nitride, and
a carbide.

14. The hard magnetic film structural body as set forth
20 in claim 12,

wherein said hard magnetic film containing Co as a
structural element has Co(110) oriented perpendicular to the
surface thereof.

15. The hard magnetic film structural body as set forth
25 in claim 12,

wherein said crystal metal base film contains at least
one element selected from the group consisting of Cr, V, Ti,
Ta, W, Zr, Nb, Hf, Mo, and Al.

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5 16. The hard magnetic film structural body as set forth
in claim 12,

wherein said crystal metal base film has a bcc (200)
orientation component.

10 17. The hard magnetic film structural body as set forth
in claim 12,

wherein the total film thickness of said crystal metal
base film and said mixing layer is 50 nm or less.

15 18. The hard magnetic film structural body as set forth
in claim 12,

wherein the average diameter of crystal grains of said
crystal metal base film is five times or more the thickness
thereof.

20 19. The hard magnetic film structural body as set forth
in claim 12,

wherein said hard magnetic film has main-grains and sub-
grains, the diameter of the main-grain being 50 nm or more,
each of the main-grains having the sub-grains.

25 20. The hard magnetic film structural body as set forth
in claim 12,

wherein said crystal metal base film and said mixing
layer are magnetic layers.

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25 21. A magnetoresistance effect device, comprising:

a substrate having a main surface;

a magnetoresistance effect film formed on the main
surface of said substrate and having a magnetic field
detecting portion;

a pair of bias magnetic field applying films disposed

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adjacent to both edge portions of the magnetic field detecting portion, the bias magnetic field applying films having hard magnetic films containing Co as a structural element and having a bi-crystal structure.

5 22. The magnetoresistance effect device as set forth in claim 21,

 wherein said hard magnetic film containing Co as a structural element has Co(110) oriented perpendicular to the surface thereof.

10 23. The magnetoresistance effect device as set forth in claim 21,

 wherein said hard magnetic film is composed of CoPt or CoCrPt.

15 24. The magnetoreisistance effect device as set forth in claim 21,

further
 further comprising a metal crystal layer as a base film of the hard magnetic film, said metal crystal layer containing at least one selected from Cr and V.

20 25. The magnetoresistance effect device as set forth in claim 21,

 wherein said magnetoresistance effect film is formed so that at least both edge portions thereof are layered on said pair of bias magnetic field applying films, said magnetoresistance effect film exchange-coupling said bias magnetic field applying films.

25 26. The magnetoresistance effect device as set forth in claim 21,

 wherein said pair of bias magnetic field applying films

Subcl 7 are abutted against said magnetoresistance effect film.

27. A magnetoresistance effect device, comprising:

a substrate having a insulating layer as a surface layer;

a magnetoresistance effect film formed on the insulating

5 layer of said substrate and having a magnetic field detecting
portion;

applying

a pair of bias magnetic field effect films disposed
adjacent to both edge portions of the magnetic field detecting
portion and having an amorphous layer, a metal crystal layer,
10 and a hard magnetic film containing Co as a structural element
successively layered on the insulating layer of said
substrate; and

a pair of electrodes for supplying a current to said
magnetoresistance effect film.

15 28. A magnetoresistance effect device as set forth in
claim 27,

wherein said amorphous layer contains structural elements
of said insulating layer of the substrate and structural
elements of said metal crystal layer.

20 29. The magnetoresistance effect device as set forth in
claim 28,

wherein said amorphous layer is a reactive layer of the
insulating layer and the metal crystal layer.

25 30. The magnetoresistance effect device as set forth in
claim 27,

wherein the metal crystal layer has a crystal metal base
film, and a reactive crystal layer.

31. The magnetoresistance effect device as set forth in

claim 27,

wherein said metal crystal layer contains at least one selected from Cr and V.

32. The magnetoresistance effect device as set forth in

5 claim 20,

wherein said insulating layer is composed of at least one selected from the group consisting of an oxide, a metal nitride, and a carbide.

33. The magnetoresistance effect device as set forth in

10 claim 27,

wherein said metal crystal layer contains at least one selected from Cr and V.

34. The magnetoresistance effect device as set forth in
claim 33,

15 wherein said hard magnetic film containing Co as a structural element has Co(110) oriented perpendicular to the surface thereof.

35. The magnetoresistance effect device as set forth in
claim 27,

20 wherein said hard magnetic film is composed of CoPt or CoCrPt.

36. The magnetoresistance effect device as set forth in
claim 27,

25 wherein said magnetoresistance effect film is formed so that at least both edge portions thereof are layered on said pair of bias magnetic field applying films, said magnetoresistance effect film exchange-coupling said bias magnetic field applying films.

37. The magnetoresistance effect device as set forth in
claim 27,

wherein said pair of bias magnetic field applying films
are abutted against said magnetoresistance effect film.

5 38. A magnetoresistance effect device, comprising:

a substrate having a main surface;
a magnetoresistance effect film formed on the main
surface of said substrate and having a magnetic field
detecting portion;

10 *applying*
a pair of bias magnetic field effect films disposed
adjacent to both edge portions of the magnetic field detecting
portion and having a crystal metal base film on the main
surface of the substrate, a mixing layer formed between the
substrate and the crystal metal base film and containing
structural elements of the substrate and structural elements
of said crystal metal base film, and a hard magnetic film
formed on the crystal metal base film and containing Co as a
structural element; and

20 a pair of electrodes for supplying a current to said
magnetoresistance effect film.

39. A magnetoresistance effect device as set forth in
claim 38,

wherein said mixing layer is an amorphous layer.

25 40. The magnetoresistance effect device as set forth in
claim 38,

wherein said crystal metal base film contains at least
one selected from Cr and V.

41. The magnetoresistance effect device as set forth in

claim 38,

wherein said substrate has a surface layer disposed on the main surface side, the surface layer being composed of at least one selected from the group consisting of an oxide, a nitride, and a carbide.

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42. The magnetoresistance effect device as set forth in claim 38,

wherein said hard magnetic film containing Co as a structural element has a bi-crystal structure.

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43. The magnetoresistance effect device as set forth in claim 42,

wherein said hard magnetic film containing Co as a structural element has Co(110) oriented perpendicular to the surface thereof.

15 44. The magnetoresistance effect device as set forth in claim 38,

wherein said hard magnetic film is composed of CoPt or CoCrPt.

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45. The magnetoresistance effect device as set forth in claim 38,

wherein said magnetoresistance effect film is formed so that at least both edge portions thereof are layered on said pair of bias magnetic field applying films, said magnetoresistance effect film exchange-coupling said bias magnetic field applying films.

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46. The magnetoresistance effect device as set forth in claim 38,

wherein said pair of bias magnetic field applying films

Subj) are abutted against said magnetoresistance effect film.

47. A magnetic head, comprising:

a lower magnetic shield layer;

Subj)
5 a magnetoresistance effect device formed on said lower magnetic shield layer through a lower reproduction magnetic gap, said magnetoresistance effect device being as set forth in claim 21, 27, or 38; and

10 an upper magnetic shield layer formed on said magnetoresistance effect device through an upper reproduction magnetic gap.

48. A magnetic recording/reproducing head, comprising:

a reproducing head having a magnetic head as set forth in claim 47;

15 *Subj*)
a recording head having a lower magnetic pole in common with said lower magnetic shield layer of said magnetic head, a record magnetic gap formed on the lower magnetic pole, an upper magnetic pole formed on the record magnetic gap, and a record coil for supplying a record magnetic field to the lower magnetic pole and the upper magnetic pole.

20 49. A magnetic record medium, comprising:

a substrate having a main surface;

25 a base film having an amorphous layer and a metal crystal layer successively layered above the main surface of said substrate;

a record layer formed on said base film and composed of a hard magnetic film containing Co as a structural element, the hard magnetic film having a bi-crystal structure; and a protection film formed on said record layer.

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50. The magnetic record medium as set forth in claim 49,
wherein said hard magnetic film containing Co as a
structural element has co(110) oriented perpendicular to the
surface thereof.

5 51. A magnetic record medium as set forth in claim 49,
wherein said amorphous layer contains structural elements
of said substrate and structural elements of said metal
crystal layer.

10 52. The magnetic record medium as set forth in claim 51,
wherein said amorphous layer is a reactive layer of the
substrate and the metal crystal layer.

15 53. The magnetic record medium as set forth in claim 49,
wherein said metal crystal layer has a crystal metal base
film, and a reactive crystal layer.

54. The magnetic record medium as set forth in claim 49,
wherein said substrate has a surface layer disposed on
the main surface side, the surface layer being composed of at
least one selected from the group consisting of an oxide, a
nitride, and a carbide.

20 55. A magnetic record medium, comprising:
a substrate having a main surface;
a base film having a metal crystal layer formed on the
main surface of said substrate, and a mixing layer between
said substrate and said metal crystal layer and containing
25 structural elements of the substrate and structural elements
of the metal crystal layer;
a record layer formed on said base film and composed of a
hard magnetic film containing Co as a structural element, the

hard magnetic film having a bi-crystal structure; and
a protection film formed on said record layer.

56. The magnetic record medium as set forth in claim 55,
wherein said hard magnetic film containing Co as a
5 structural element has Co(110) oriented perpendicular to the
surface thereof.

57. The magnetic record medium as set forth in claim 55,
wherein said substrate has a surface layer disposed on
the main surface side, the surface layer being composed of at
10 least one selected from the group consisting of an oxide, a
nitride, and a carbide.

58. A magnetic storing apparatus, comprising:
the magnetoresistance effect device of claim 21, 27, or
38;
15 a write electrode for storing information to the
magnetoresistance effect film of the magnetoresistance effect
device; and
a read electrode, composed of the electrode of the
magnetoresistance effect device, for reproducing information
20 stored in the magnetoresistance effect film.

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